## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10562226	NAKAMURA, TOSHIO
Examiner	Art Unit
Strieb, Michael A	2809

SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES				
Search Notes	Date	Examiner		
Met with Benny Tieu	08/30/2007	MAS		
Met with Sam Walk	8/30/2007	MAS		
EAST text search	8/31/2007	MAS		
Consulted with Primary Examiner William Perkey	6/5/2008	MAS		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		

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